

Docket No.: SAA-002

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :  
Nobukatsu NISHIDA et al. :  
U.S. Patent Application No. *not yet assigned* :  
Filed: *herewith* :

For: METHOD, SYSTEM, AND APPARATUS FOR DETACHING AND COLLECTING AN IC  
TAG FROM A PAPER SHEET TO WHICH IT IS ATTACHED

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the application and no certification or fee is required.

Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above-identified application and readily available to the Examiner. Therefore it is believed that Applicants have met all requirements regarding duty of disclosure under 37 CFR 1.56. A copy of the foreign search report is attached for the Examiner's information. Acknowledgement and consideration of these documents are respectfully requested.

Respectfully submitted,

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# INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
SAA-002

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Not yet assigned

APPLICANT  
Nobukatsu NISHIDA et al.

FILING DATE  
herewith

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	2003-16415A	01-17-2003	JP				
	2002-236889	08-23-2002	JP				
	9-38629A	02-10-1997	JP				
	52-125582A	10-27-1977	JP				
	2002-211755A	07-31-2002	JP				
	2001-334530A	12-04-2001	JP				
	2001-167240	06-22-2001	JP				
	2001-14442	01-10-2001	JP				
	2000-194820	07-14-2000	JP				
	2003-108962	04-11-2003	JP				

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.